In the Claims:

Please amend the claims as follows. A complete listing of the claims proper claim identifiers is set forth below.

1. (Currently Amended) A method for the monitoring of a manufacturing process of a plurality of physical objects, the method comprising the steps of:

~~in which an analysis is performed~~ performing an analysis by using values of at least one process parameter of the manufacturing process of the physical object;

~~in which, as a result of the analysis,~~ determining when they do not satisfy a prescribed selection criterion[[,]]; and

~~physical objects are marked~~ marking the physical objects in such a way that the associated physical objects are to be sent for a special measurement.

2. (Original) The method as claimed in claim 1, in which the physical object is a wafer.

3. (Original) The method as claimed in claim 1 or 2, in which the analysis is a statistical analysis.

4. (Original) The method as claimed in one of claims 1 to 3, in which the values of the at least one process parameter are measured when the physical object is being manufactured.

5. (Original) The method as claimed in one of claims 1 to 4, in which at least one marked physical object is sent for a special measurement.

6. (Original) The method as claimed in claim 5, in which the special measurement is a measurement for checking the quality of the physical object marked.

7. (Original) The method as claimed in one of claims 1 to 6, in which the physical objects not marked are further treated according to the manufacturing process.

8. (Original) The method as claimed in one of claims 1 to 7, in which the selection criterion is a quality characteristic of the manufacturing process.

9. (Original) The method as claimed in one of claims 1 to 8, in which the selection criterion is considered as not satisfied if a value of the at least one process parameter goes above or below a prescribed limit value.

10. (Currently Amended) A device for the monitoring of a manufacturing process of a plurality of physical objects with a processor which is set up in such a way that the following method steps can be carried out:

~~performance~~ performing ~~of~~ an analysis by using values of at least one process parameter of the manufacturing process of the physical object;

marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not satisfied~~, so that~~; and

sending the associated physical objects ~~are to be sent~~ for special treatments.

11. (Currently Amended) A computer-readable storage medium, in which a program for the monitoring of a manufacturing process of a plurality of physical objects is stored, which program ~~has~~ performs the following method steps when it is run by a processor:

~~performance of an~~ performing analysis by using values of at least one process parameter of the manufacturing process of the physical object;

marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not satisfied~~, so that~~; and

sending the associated physical objects ~~are to be sent~~ for special treatments.

12. (Currently Amended) A computer program element for the monitoring of a manufacturing process of a plurality of physical objects, which has the following method steps when it is run by a processor:

~~performance of~~ performing an analysis by using values of at least one process parameter of the manufacturing process of the physical object;

marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not satisfied~~, so that~~; and

sending the associated physical objects ~~are to be sent~~ for special treatments.